

Notice of References Cited	Application/Control No. 10/673,993	Applicant(s)/Patent Under Reexamination TAKAHASHI ET AL.	
	Examiner Lynne Edmondson	Art Unit 1725	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0037435	03-2002	Hirashima et al.	428/693
*	B	US-6,183,875	02-2001	Ning et al.	428/472
*	C	US-4,602,731	07-1986	Dockus, Kostas F.	228/121
*	D	US-6,670,216	12-2003	Strauch, Gerhard	438/106
*	E	US-5,144,885	09-1992	Suzuki et al.	92/222
*	F	US-5,196,756	03-1993	Kohno et al.	310/328
*	G	US-2004/0149689	08-2004	Ning et al.	216/083
*	H	US-2002/0164488	11-2002	Furo et al.	428/469
*	I	US-6,309,737	10-2001	Hirashima et al.	428/210
	J	US-6,066,205	05-2000	Hunter, Charles Eric	117/200
	K	US-4,929,433	05-1990	Hexemer et al.	423/411
	L	US-5,571,603	11-1996	Utumi et al.	428/212
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2005008432 A	01-2005	Japan	IWATA et al.	C01B 21/072
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.